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Toote geomeetriline kirjeldus ja tehnilised andmed (GPS). Pinnatekstuur: profiilimeetod. Terminid, määratlused ja pinnatekstuuri parameetrid

Geometrical product specifications (GPS) - Surface texture: Profile method - Terms, definitions and surface texture parameters

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

<p>Käesolev Eesti standard EVS-EN ISO 4287:1999 sisaldab Euroopa standardi EN ISO 4287:1998 ingliskeelset teksti.</p> <p>Käesolev dokument on jõustatud 12.12.1999 ja selle kohta on avaldatud teade Eesti standardiorganisatsiooni ametlikus väljaandes.</p> <p>Standard on kättesaadav Eesti standardiorganisatsioonist.</p>	<p>This Estonian standard EVS-EN ISO 4287:1999 consists of the English text of the European standard EN ISO 4287:1998.</p> <p>This document is endorsed on 12.12.1999 with the notification being published in the official publication of the Estonian national standardisation organisation.</p> <p>The standard is available from Estonian standardisation organisation.</p>
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<p>Käsitlusala: Käesolev rahvusvaheline standard esitab terminid, määratlused ja parameetrid pinnatekstuuri (karedus, lainelisus ja põhiprofiil) määramiseks profiilimeetoditega.</p>	<p>Scope:</p>
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ICS 01.040.17, 17.040.20

Võtmesõnad: karedus, pinna lainelisus, pinna omadused, pinna seisund, sõnastik, tekstuuri profiilid, toote geomeetiline kirjeldus ja tehnilised andmed

ICS 01.040.17; 17.040.20

Descriptors: GPS, surface texture, concepts.

English version

Geometrical product specifications (GPS)
Surface texture: Profile method

Terms, definitions and surface texture parameters
(ISO 4287 : 1997)

Spécification géométrique des
produits (GPS) – État de surface:
Méthode du profil – Termes,
définitions et paramètres d'état de
surface (ISO 4287 : 1997)

Geometrische Produktspezifikationen
(GPS) – Oberflächenbeschaffenheit:
Tastschnittverfahren – Benennungen,
Definitionen und Kenngrößen der
Oberflächenbeschaffenheit
(ISO 4287 : 1997)

This European Standard was approved by CEN on 1998-01-26.

CEN members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CEN member.

The European Standards exist in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CEN member into its own language and notified to the Central Secretariat has the same status as the official versions.

CEN members are the national standards bodies of Austria, Belgium, the Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, the Netherlands, Norway, Portugal, Spain, Sweden, Switzerland, and the United Kingdom.

CEN

European Committee for Standardization
Comité Européen de Normalisation
Europäisches Komitee für Normung

Central Secretariat: rue de Stassart 36, B-1050 Brussels

Foreword

International Standard

ISO 4287 : 1997 Geometrical product specifications (GPS) – Surface texture: Profile method – Terms, definitions and surface texture parameters,

which was prepared by ISO/TC 213 'Dimensional and geometrical product specifications and verification' (formerly ISO/TC 57) of the International Organization for Standardization, has been adopted by Technical Committee CEN/TC 290 'Dimensional and geometrical product specifications and verification', the Secretariat of which is held by DIN, as a European Standard.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, and conflicting national standards withdrawn, by February 1999 at the latest.

In accordance with the CEN/CENELEC Internal Regulations, the national standards organizations of the following countries are bound to implement this European Standard:

Austria, Belgium, the Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, the Netherlands, Norway, Portugal, Spain, Sweden, Switzerland, and the United Kingdom.

Endorsement notice

The text of the International Standard ISO 4287 : 1997 was approved by CEN as a European Standard without any modification.

NOTE: Normative references to international publications are listed in Annex ZA (normative).

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Introduction

This International Standard is a Geometrical Product Specification (GPS) standard and is to be regarded as a General GPS standard (see ISO/TR 14638). It influences chain link 2 of the chains of standards on surface texture.

For more detailed information on the relationship of this International Standard to other standards and the GPS matrix model, see annex E.

Historically, the roughness profile and its parameters have been the only parts of surface texture characterization that have been well defined.

A default relationship between λ_c and λ_f is under consideration.

1 Scope

This International Standard specifies terms, definitions and parameters for the determination of surface texture (roughness, waviness and primary profile) by profiling methods.

2 Normative references

The following standards contain provisions which, through reference in this text, constitute provisions of this International Standard. At the time of publication, the editions indicated were valid. All standards are subject to revision, and parties to agreements based on this International Standard are encouraged to investigate the possibility of applying the most recent editions of the standards indicated below. Members of IEC and ISO maintain registers of currently valid International Standards.

ISO 3274:1996, *Geometrical Product Specifications (GPS) — Surface texture: Profile method — Nominal characteristics of contact (stylus) instruments*.

ISO 4288:1996, *Geometrical Product Specifications (GPS) — Surface texture: Profile method — Rules and procedures for the assessment of surface texture*.

ISO 11562:1996, *Geometrical Product Specifications (GPS) — Surface texture: Profile method — Metrological characterization of phase correct filters*.

1 Domaine d'application

La présente Norme internationale prescrit les termes, définitions et paramètres pour la détermination de l'état de surface (profils de rugosité, d'ondulation et profil primaire) par les méthodes de profil.

2 Références normatives

Les normes suivantes contiennent des dispositions qui, par suite de la référence qui en est faite, constituent des dispositions valables pour la présente Norme internationale. Au moment de la publication, les éditions indiquées étaient en vigueur. Toute norme est sujette à révision et les parties prenantes des accords fondés sur la présente Norme internationale sont invitées à rechercher la possibilité d'appliquer les éditions les plus récentes des normes indiquées ci-après. Les membres de la CEI et de l'ISO possèdent le registre des Normes internationales en vigueur à un moment donné.

ISO 3274:1996, *Spécification géométrique des produits (GPS) — État de surface: Méthode du profil — Caractéristiques nominales des instruments à contact (palpeur)*.

ISO 4288:1996, *Spécification géométrique des produits (GPS) — État de surface: Méthode du profil — Règles et procédures pour l'évaluation de l'état de surface*.

ISO 11562:1996, *Spécification géométrique des produits (GPS) — État de surface: Méthode du profil — Caractéristiques métrologiques des filtres à phase correcte*.